







Report No.: EED32N80236501

## PHOTOGRAPHS OF TEST SETUP

Test model No.: G1106



Radiated spurious emission Test Setup-1(Below 30MHz)



Radiated spurious emission Test Setup-2(Below 1GHz)













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Radiated spurious emission Test Setup-3(Above 1GHz)



**Conducted Emissions Test Setup** 



















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Radiated spurious emission Test Setup-4(Above 1GHz) There are absorbing materials under the ground.





















































